



## PL4009

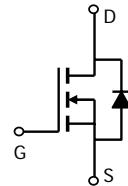
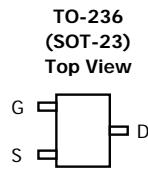
### N-Channel Enhancement Mode Field Effect Transistor

#### General Description

The PL4009 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications. Standard Product PL4009 is Pb-free (meets ROHS & Sony 259 specifications). PL4009A is a Green Product ordering option. PL4009 and PL4009A are electrically identical.

#### Features

$V_{DS}$  (V) = 30V  
 $I_D$  = 5.8 A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 28m\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 33m\Omega$  ( $V_{GS}$  = 4.5V)  
 $R_{DS(ON)} < 52m\Omega$  ( $V_{GS}$  = 2.5V)



#### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	5.8	A
$T_A=70^\circ C$		4.9	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	
Power Dissipation <sup>A</sup>	$P_D$	1.4	W
$T_A=70^\circ C$		1	
Junction and Storage Temperature Range	$T_J$ , $T_{STG}$	-55 to 150	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	65	90	°C/W
Steady-State		85	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	43	60	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1		$\mu\text{A}$
				5		
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.7	1.1	1.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5.8\text{A}$ $T_J=125^\circ\text{C}$		22.8	28	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=5\text{A}$		32	39	
		$V_{GS}=2.5\text{V}, I_D=4\text{A}$		27.3	33	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5\text{A}$	10	15		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.71	1	V
$I_s$	Maximum Body-Diode Continuous Current				2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		823	1030	pF
$C_{\text{oss}}$	Output Capacitance			99		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			77		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.2	3.6	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=5.8\text{A}$		9.7	12	nC
$Q_{\text{gs}}$	Gate Source Charge			1.6		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.1		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.7\Omega, R_{\text{GEN}}=3\Omega$		3.3	5	ns
$t_r$	Turn-On Rise Time			4.8	7	ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			26.3	40	ns
$t_f$	Turn-Off Fall Time			4.1	6	ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16	20	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8.9	12	nC

A: The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $\leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QJL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

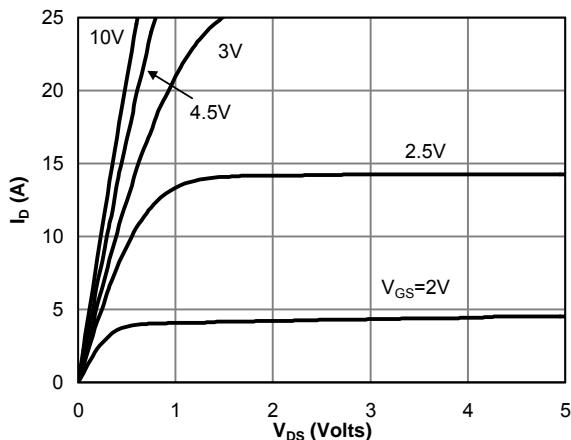


Fig 1: On-Region Characteristics

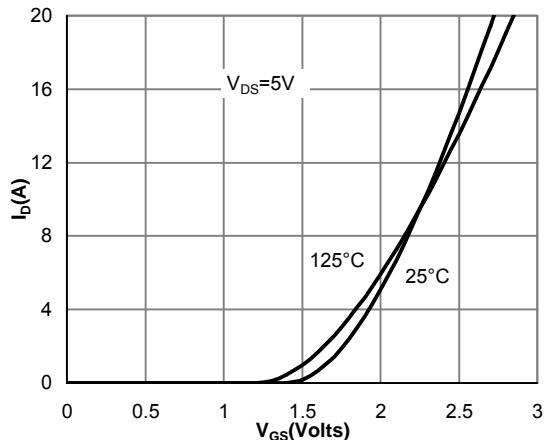


Figure 2: Transfer Characteristics

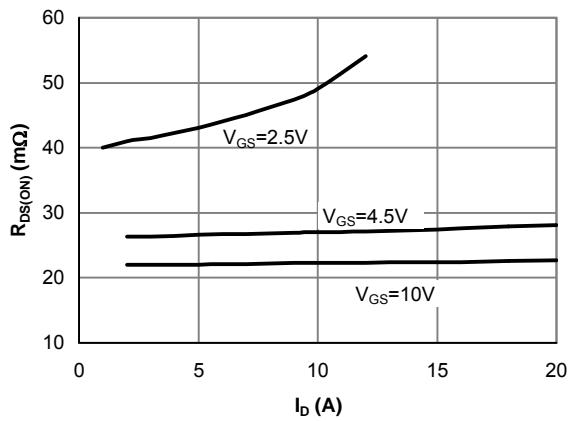


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

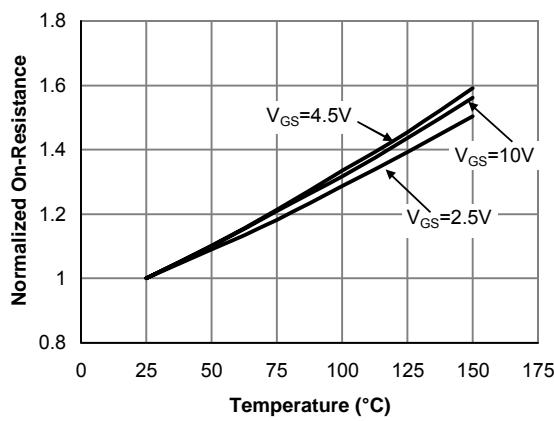


Figure 4: On-Resistance vs. Junction Temperature

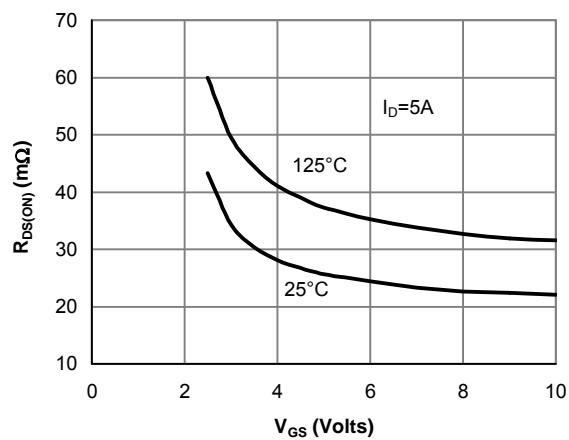


Figure 5: On-Resistance vs. Gate-Source Voltage

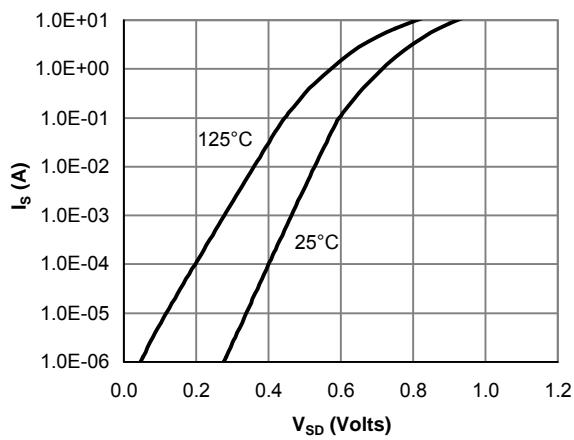


Figure 6: Body-Diode Characteristics



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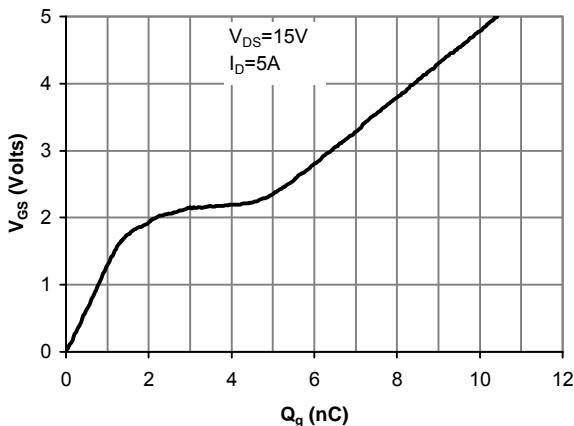


Figure 7: Gate-Charge Characteristics

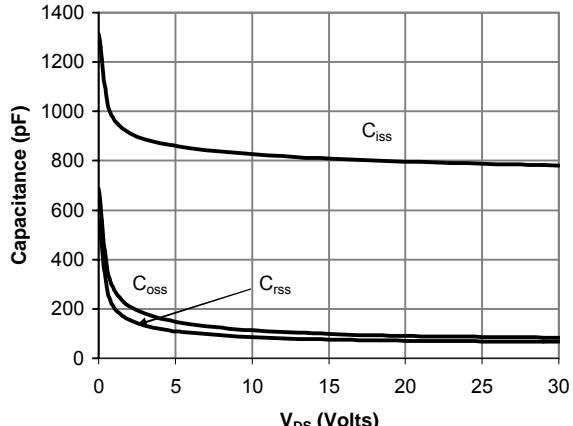


Figure 8: Capacitance Characteristics

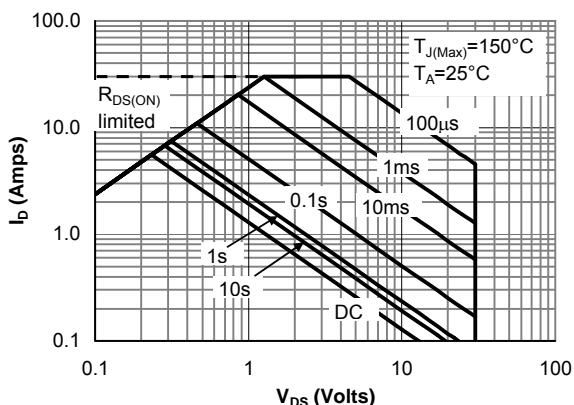


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

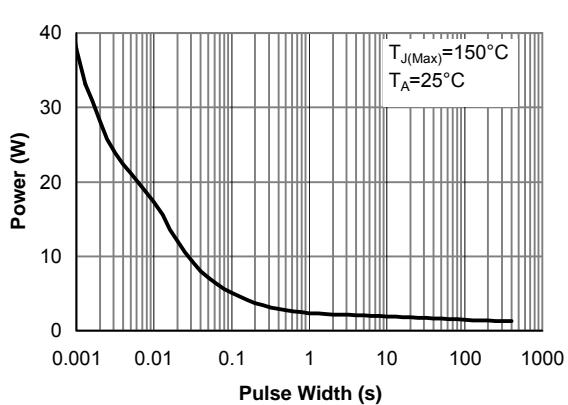


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

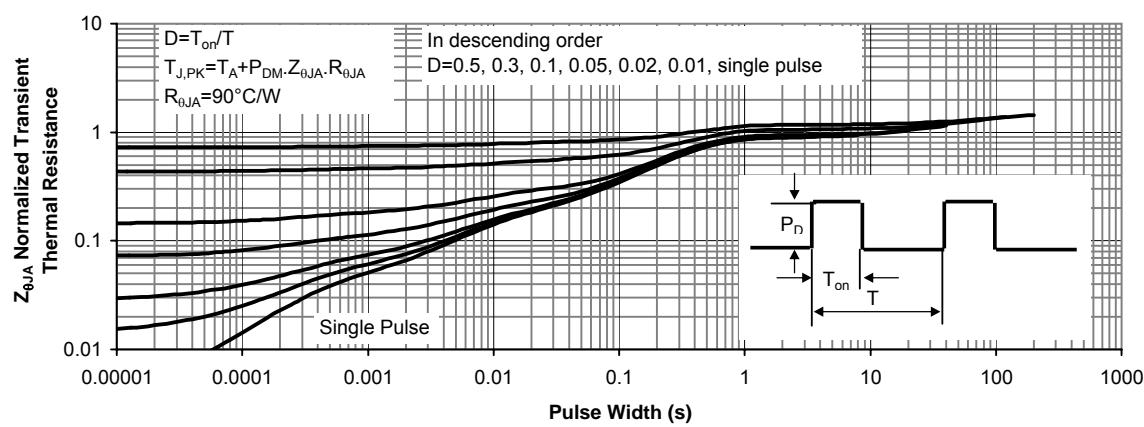


Figure 11: Normalized Maximum Transient Thermal Impedance